

FORM PTO-1448 <i>OIP</i> INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>APR 09 2002</i> (USE SEVERAL SHEETS IF NECESSARY)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASMXEX.367A	APPLICATION NO. 10/074,534
		APPLICANT Michael A. Todd	
		FILING DATE February 11, 2002	GROUP 2814

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
<i>SM</i>	5,389,570	02/14/95	Shiozawa			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

<i>SM</i>					
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EXAMINER <i>SM</i>	DATE CONSIDERED <i>9/27/2004</i>
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

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		FILING DATE February 11, 2002	GROUP 2812

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

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INITIAL**

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

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EXAMINER DUPLICATE - ORIGINAL

DATE CONSIDERED

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<p>APPLICANT Michael A. Todd</p>		
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U.S. PATENT DOCUMENTS

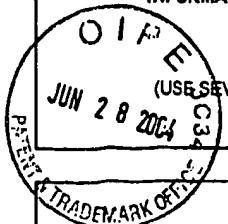
FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
<i>SM</i>	1	V. Z-Q Li <i>et al.</i> , Appl. Phys. Lett. 71(23) 3388-90 (1997)
	2	T-J King <i>et al.</i> , J. Electrochem. Soc., 141(8) 2235-41 (1994)
	3	A. Kovalgin <i>et al.</i> , ProRISC/IEEE 311-17 (1998)
	4	C. Hernandez <i>et al.</i> , Mat. Res. Soc. Symp. Proc. 533 93-98 (1998)
	5	M. Cao <i>et al.</i> , J. Electrochem. Soc., 142(5) 1566-72 (1995)
<i>SM</i>	6	J. Holleman <i>et al.</i> , J. Electrochem. Soc. 140(6) 1717-22 (1993)

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
1. <i>SM</i>	5,214,002	05/25/93	Hayashi et al.			
2. <i>/</i>	5,356,821	10/18/94	Naruse et al.			
3. <i>/</i>	5,471,330	11/28/95	Sarma			
4. <i>/</i>	6,103,600	08/15/00	Ueda et al.			
<i>SM</i>						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
5. <i>SM</i>	11317530	16-11-99	Japan (abstract)			X	
6. <i>/</i>	EP 0368651 A2	18-05-90					
7. <i>/</i>	EP 0486047 A2	20-05-92					
8. <i>/</i>	EP 0747974 A2	11-12-96					
9. <i>/</i>	EP 1065728 A2	03-01-01					
10. <i>SM</i>	GB 2332564 A	23-06-99	United Kingdom				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
<i>SM</i>	Olivares, J. et al.; "Solid-phase crystallization of amorphous SiGe films deposited by LPCVD on SiO ₂ and glass," Thin Solid Films 337 (1999) pp. 51-54.

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7. Ikoma et al., Growth of Si/3C-SiC/Si(100) heterostructures by pulsed supersonic free jets, *Applied Physics Letters*, Volume 75, No. 25, Pg. 3977-3979, December 1999

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